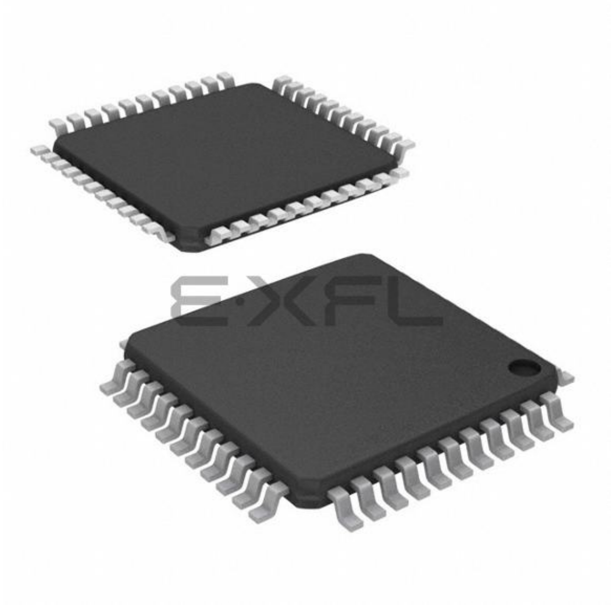

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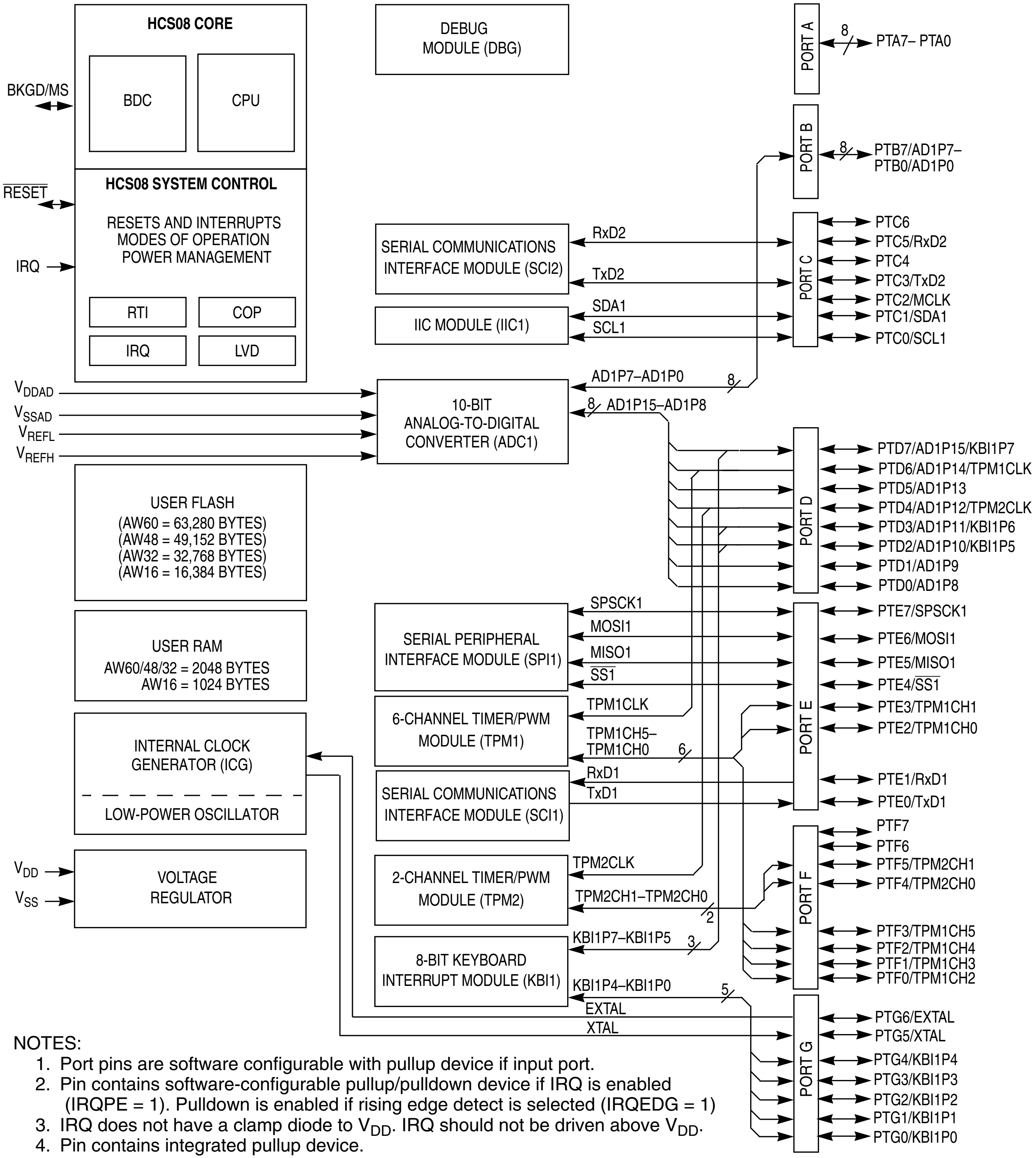
Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	40MHz
Connectivity	I²C, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	34
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	44-LQFP
Supplier Device Package	44-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/s9s08aw32e5vfge

Part Number	Package Description	Original (gold wire) package document number	Current (copper wire) package document number
MC68HC908JW32	48 QFN	98ARH99048A	98ASA00466D
MC9S08AC16			
MC9S908AC60			
MC9S08AC128			
MC9S08AW60			
MC9S08GB60A			
MC9S08GT16A			
MC9S08JM16			
MC9S08JM60			
MC9S08LL16			
MC9S08QE128			
MC9S08QE32			
MC9S08RG60			
MCF51CN128			
MC9RS08LA8	48 QFN	98ARL10606D	98ASA00466D
MC9S08GT16A	32 QFN	98ARH99035A	98ASA00473D
MC9S908QE32	32 QFN	98ARE10566D	98ASA00473D
MC9S908QE8	32 QFN	98ASA00071D	98ASA00736D
MC9S08JS16	24 QFN	98ARL10608D	98ASA00734D
MC9S08QB8			
MC9S08QG8	24 QFN	98ARL10605D	98ASA00474D
MC9S08SH8	24 QFN	98ARE10714D	98ASA00474D
MC9RS08KB12	24 QFN	98ASA00087D	98ASA00602D
MC9S08QG8	16 QFN	98ARE10614D	98ASA00671D
MC9RS08KB12	8 DFN	98ARL10557D	98ASA00672D
MC9S08QG8			
MC9RS08KA2	6 DFN	98ARL10602D	98ASA00735D

Chapter 6
Parallel Input/Output

Chapter 7
Central Processor Unit (S08CPUV2)



NOTES:

1. Port pins are software configurable with pullup device if input port.
2. Pin contains software-configurable pullup/pulldown device if IRQ is enabled (IRQPE = 1). Pulldown is enabled if rising edge detect is selected (IRQEDG = 1)
3. IRQ does not have a clamp diode to V_{DD}. IRQ should not be driven above V_{DD}.
4. Pin contains integrated pullup device.
5. Pins PTD7, PTD3, PTD2, and PTG4 contain both pullup and pulldown devices. Pulldown enabled when KBI is enabled (KBIPEn = 1) and rising edge is selected (KBEDGn = 1).

Figure 1-1. MC9S08AW60 Series Block Diagram

Table 4-3. High-Page Register Summary (Sheet 2 of 2)

Address	Register Name	Bit 7	6	5	4	3	2	1	Bit 0
$1846	**PTBDS**	PTBDS7	PTBDS6	PTBDS5	PTBDS4	PTBDS3	PTBDS2	PTBDS1	PTBDS0
$1847	Reserved	—	—	—	—	—	—	—	—
$1848	**PTCPE**	0	PTCPE6	PTCPE5	PTCPE4	PTCPE3	PTCPE2	PTCPE1	PTCPE0
$1849	**PTCSE**	0	PTCSE6	PTCSE5	PTCSE4	PTCSE3	PTCSE2	PTCSE1	PTCSE0
$184A	**PTCDS**	0	PTCDS6	PTCDS5	PTCDS4	PTCDS3	PTCDS2	PTCDS1	PTCDS0
$184B	Reserved	—	—	—	—	—	—	—	—
$184C	**PTDPE**	PTDPE7	PTDPE6	PTDPE5	PTDPE4	PTDPE3	PTDPE2	PTDPE1	PTDPE0
$184D	**PTDSE**	PTDSE7	PTDSE6	PTDSE5	PTDSE4	PTDSE3	PTDSE2	PTDSE1	PTDSE0
$184E	**PTDDS**	PTDDS7	PTDDS6	PTDDS5	PTDDS4	PTDDS3	PTDDS2	PTDDS1	PTDDS0
$184F	Reserved	—	—	—	—	—	—	—	—
$1850	**PTEPE**	PTEPE7	PTEPE6	PTEPE5	PTEPE4	PTEPE3	PTEPE2	PTEPE1	PTEPE0
$1851	**PTESE**	PTESE7	PTESE6	PTESE5	PTESE4	PTESE3	PTESE2	PTESE1	PTESE0
$1852	**PTEDS**	PTEDS7	PTEDS6	PTEDS5	PTEDS4	PTEDS3	PTEDS2	PTEDS1	PTEDS0
$1853	Reserved	—	—	—	—	—	—	—	—
$1854	**PTFPE**	PTFPE7	PTFPE6	PTFPE5	PTFPE4	PTFPE3	PTFPE2	PTFPE1	PTFPE0
$1855	**PTFSE**	PTFSE7	PTFSE6	PTFSE5	PTFSE4	PTFSE3	PTFSE2	PTFSE1	PTFSE0
$1856	**PTFDS**	PTFDS7	PTFDS6	PTFDS5	PTFDS4	PTFDS3	PTFDS2	PTFDS1	PTFDS0
$1857	Reserved	—	—	—	—	—	—	—	—
$1858	**PTGPE**	0	PTGPE6	PTGPE5	PTGPE4	PTGPE3	PTGPE2	PTGPE1	PTGPE0
$1859	**PTGSE**	0	PTGSE6	PTGSE5	PTGSE4	PTGSE3	PTGSE2	PTGSE1	PTGSE0
$185A	**PTGDS**	0	PTGDS6	PTGDS5	PTGDS4	PTGDS3	PTGDS2	PTGDS1	PTGDS0
$185B– $185F	Reserved	— —	— —	— —	— —	— —	— —	— —	— —

[1] This reserved bit must always be written to 0.

Nonvolatile FLASH registers, shown in Table 4-4, are located in the FLASH memory. These registers include an 8-byte backdoor key which optionally can be used to gain access to secure memory resources. During reset events, the contents of NVPROT and NVOPT in the nonvolatile register area of the FLASH memory are transferred into corresponding FPROT and FOPT working registers in the high-page registers to control security and block protection options.

4.6.6 FLASH Command Register (FCMD)

Only five command codes are recognized in normal user modes as shown in Table 4-14. Refer to Section 4.4.3, “Program and Erase Command Execution” for a detailed discussion of FLASH programming and erase operations.

	7	6	5	4	3	2	1	0
R	0	0	0	0	0	0	0	0
W	FCMD7	FCMD6	FCMD5	FCMD4	FCMD3	FCMD2	FCMD1	FCMD0
Reset	0	0	0	0	0	0	0	0

Figure 4-11. FLASH Command Register (FCMD)

Table 4-13. FCMD Register Field Descriptions

Field	Description
FCMD[7:0]	**FLASH Command Bits** — See Table 4-14

Table 4-14. FLASH Commands

Command	FCMD	Equate File Label
Blank check	$05	mBlank
Byte program	$20	mByteProg
Byte program — burst mode	$25	mBurstProg
Page erase (512 bytes/page)	$40	mPageErase
Mass erase (all FLASH)	$41	mMassErase

All other command codes are illegal and generate an access error.

It is not necessary to perform a blank check command after a mass erase operation. Only blank check is required as part of the security unlocking mechanism.

Table 5-3. SRS Register Field Descriptions (continued)

Field	Description
2 ICG	**Internal Clock Generation Module Reset** — Reset was caused by an ICG module reset. 0 Reset not caused by ICG module. 1 Reset caused by ICG module.
1 LVD	**Low Voltage Detect** — If the LVDRE and LVDSE bits are set and the supply drops below the LVD trip voltage, an LVD reset will occur. This bit is also set by POR. 0 Reset not caused by LVD trip or POR. 1 Reset caused by LVD trip or POR.

5.9.3 System Background Debug Force Reset Register (SBDFR)

This register contains a single write-only control bit. A serial background command such as WRITE_BYTE must be used to write to SBDFR. Attempts to write this register from a user program are ignored. Reads always return $00.

	7	6	5	4	3	2	1	0
R	0	0	0	0	0	0	0	0
W	▨	▨	▨	▨	▨	▨	▨	BDFR[1]
Reset	0	0	0	0	0	0	0	0

▨ = Unimplemented or Reserved

---

[1] BDFR is writable only through serial background debug commands, not from user programs.

Figure 5-4. System Background Debug Force Reset Register (SBDFR)

Table 5-4. SBDFR Register Field Descriptions

Field	Description
0 BDFR	**Background Debug Force Reset** — A serial background command such as WRITE_BYTE may be used to allow an external debug host to force a target system reset. Writing logic 1 to this bit forces an MCU reset. This bit cannot be written from a user program.

5.9.4 System Options Register (SOPT)

This register may be read at any time. Bits 3 and 2 are unimplemented and always read 0. This is a write-once register so only the first write after reset is honored. Any subsequent attempt to write to SOPT (intentionally or unintentionally) is ignored to avoid accidental changes to these sensitive settings. SOPT should be written during the user's reset initialization program to set the desired controls even if the desired settings are the same as the reset settings.

8.4.4 FLL Engaged Internal Unlocked

FEI unlocked is a temporary state that is entered when FEI is entered and the count error (Δn) output from the subtractor is greater than the maximum n_{unlock} or less than the minimum n_{unlock}, as required by the lock detector to detect the unlock condition.

The ICG will remain in this state while the count error (Δn) is greater than the maximum n_{lock} or less than the minimum n_{lock}, as required by the lock detector to detect the lock condition.

In this state the output clock signal ICGOUT frequency is given by $f_{ICGDCLK}$ / R.

8.4.5 FLL Engaged Internal Locked

FLL engaged internal locked is entered from FEI unlocked when the count error (Δn), which comes from the subtractor, is less than n_{lock} (max) and greater than n_{lock} (min) for a given number of samples, as required by the lock detector to detect the lock condition. The output clock signal ICGOUT frequency is given by $f_{ICGDCLK}$ / R. In FEI locked, the filter value is updated only once every four comparison cycles. The update made is an average of the error measurements taken in the four previous comparisons.

8.4.6 FLL Bypassed, External Clock (FBE) Mode

FLL bypassed external (FBE) is entered when any of the following conditions occur:

- From SCM when CLKS = 10 and ERCS is high
- When CLKS = 10, ERCS = 1 upon entering off mode, and off is then exited
- From FLL engaged external mode if a loss of DCO clock occurs and the external reference remains valid (both LOCS = 1 and ERCS = 1)

In this state, the DCO and IRG are off and the reference clock is derived from the external reference clock, ICGERCLK. The output clock signal ICGOUT frequency is given by $f_{ICGERCLK}$ / R. If an external clock source is used (REFS = 0), then the input frequency on the EXTAL pin can be anywhere in the range 0 MHz to 40 MHz. If a crystal or resonator is used (REFS = 1), then frequency range is either low for RANGE = 0 or high for RANGE = 1.

8.4.7 FLL Engaged, External Clock (FEE) Mode

The FLL engaged external (FEE) mode is entered when any of the following conditions occur:

- CLKS = 11 and ERCS and DCOS are both high.
- The DCO stabilizes (DCOS = 1) while in SCM upon exiting the off state with CLKS = 11.

In FEE mode, the reference clock is derived from the external reference clock ICGERCLK, and the FLL loop will attempt to lock the ICGDCLK frequency to the desired value, as selected by the MFD bits. To run in FEE mode, there must be a working 32 kHz–100 kHz or 2 MHz–10 MHz external clock source. The maximum external clock frequency is limited to 10 MHz in FEE mode to prevent over-clocking the DCO. The minimum multiplier for the FLL, from Table 8-12 is 4. Because 4 X 10 MHz is 40MHz, which is the operational limit of the DCO, the reference clock cannot be any faster than 10 MHz.

10.6.3 Channel Event Interrupt Description

The meaning of channel interrupts depends on the current mode of the channel (input capture, output compare, edge-aligned PWM, or center-aligned PWM).

When a channel is configured as an input capture channel, the ELSnB:ELSnA control bits select rising edges, falling edges, any edge, or no edge (off) as the edge that triggers an input capture event. When the selected edge is detected, the interrupt flag is set. The flag is cleared by the 2-step sequence described in Section 10.6.1, “Clearing Timer Interrupt Flags.”

When a channel is configured as an output compare channel, the interrupt flag is set each time the main timer counter matches the 16-bit value in the channel value register. The flag is cleared by the 2-step sequence described in Section 10.6.1, “Clearing Timer Interrupt Flags.”

10.6.4 PWM End-of-Duty-Cycle Events

For channels that are configured for PWM operation, there are two possibilities:

- When the channel is configured for edge-aligned PWM, the channel flag is set when the timer counter matches the channel value register that marks the end of the active duty cycle period.
- When the channel is configured for center-aligned PWM, the timer count matches the channel value register twice during each PWM cycle. In this CPWM case, the channel flag is set at the start and at the end of the active duty cycle, which are the times when the timer counter matches the channel value register.

The flag is cleared by the 2-step sequence described in Section 10.6.1, “Clearing Timer Interrupt Flags.”

Table 11-4. SCIxC2 Register Field Descriptions (continued)

Field	Description
1 RWU	**Receiver Wakeup Control** — This bit can be written to 1 to place the SCI receiver in a standby state where it waits for automatic hardware detection of a selected wakeup condition. The wakeup condition is either an idle line between messages (WAKE = 0, idle-line wakeup), or a logic 1 in the most significant data bit in a character (WAKE = 1, address-mark wakeup). Application software sets RWU and (normally) a selected hardware condition automatically clears RWU. Refer to Section 11.3.3.2, “Receiver Wakeup Operation” for more details. 0 Normal SCI receiver operation. 1 SCI receiver in standby waiting for wakeup condition.
0 SBK	**Send Break** — Writing a 1 and then a 0 to SBK queues a break character in the transmit data stream. Additional break characters of 10 or 11 bit times of logic 0 are queued as long as SBK = 1. Depending on the timing of the set and clear of SBK relative to the information currently being transmitted, a second break character may be queued before software clears SBK. Refer to Section 11.3.2.1, “Send Break and Queued Idle” for more details. 0 Normal transmitter operation. 1 Queue break character(s) to be sent.

11.2.4 SCI Status Register 1 (SCIxS1)

This register has eight read-only status flags. Writes have no effect. Special software sequences (which do not involve writing to this register) are used to clear these status flags.

	7	6	5	4	3	2	1	0
R	TDRE	TC	RDRF	IDLE	OR	NF	FE	PF
W	▨	▨	▨	▨	▨	▨	▨	▨
Reset	1	1	0	0	0	0	0	0

▨ = Unimplemented or Reserved

Figure 11-8. SCI Status Register 1 (SCIxS1)

Table 11-5. SCIxS1 Register Field Descriptions

Field	Description
7 TDRE	**Transmit Data Register Empty Flag** — TDRE is set out of reset and when a transmit data value transfers from the transmit data buffer to the transmit shifter, leaving room for a new character in the buffer. To clear TDRE, read SCIxS1 with TDRE = 1 and then write to the SCI data register (SCIxD). 0 Transmit data register (buffer) full. 1 Transmit data register (buffer) empty.
6 TC	**Transmission Complete Flag** — TC is set out of reset and when TDRE = 1 and no data, preamble, or break character is being transmitted. 0 Transmitter active (sending data, a preamble, or a break). 1 Transmitter idle (transmission activity complete). TC is cleared automatically by reading SCIxS1 with TC = 1 and then doing one of the following three things: • Write to the SCI data register (SCIxD) to transmit new data • Queue a preamble by changing TE from 0 to 1 • Queue a break character by writing 1 to SBK in SCIxC2

Table 11-7. SCIxC3 Register Field Descriptions (continued)

Field	Description
5 TXDIR	**TxD Pin Direction in Single-Wire Mode** — When the SCI is configured for single-wire half-duplex operation (LOOPS = RSRC = 1), this bit determines the direction of data at the TxD pin. 0 TxD pin is an input in single-wire mode. 1 TxD pin is an output in single-wire mode.
4 TXINV[1]	**Transmit Data Inversion** — Setting this bit reverses the polarity of the transmitted data output. 0 Transmit data not inverted 1 Transmit data inverted
3 ORIE	**Overrun Interrupt Enable** — This bit enables the overrun flag (OR) to generate hardware interrupt requests. 0 OR interrupts disabled (use polling). 1 Hardware interrupt requested when OR = 1.
2 NEIE	**Noise Error Interrupt Enable** — This bit enables the noise flag (NF) to generate hardware interrupt requests. 0 NF interrupts disabled (use polling). 1 Hardware interrupt requested when NF = 1.
1 FEIE	**Framing Error Interrupt Enable** — This bit enables the framing error flag (FE) to generate hardware interrupt requests. 0 FE interrupts disabled (use polling). 1 Hardware interrupt requested when FE = 1.
0 PEIE	**Parity Error Interrupt Enable** — This bit enables the parity error flag (PF) to generate hardware interrupt requests. 0 PF interrupts disabled (use polling). 1 Hardware interrupt requested when PF = 1.

[1] Setting TXINV inverts the TxD output for all cases: data bits, start and stop bits, break, and idle.

11.2.7 SCI Data Register (SCIxD)

This register is actually two separate registers. Reads return the contents of the read-only receive data buffer and writes go to the write-only transmit data buffer. Reads and writes of this register are also involved in the automatic flag clearing mechanisms for the SCI status flags.

	7	6	5	4	3	2	1	0
R	R7	R6	R5	R4	R3	R2	R1	R0
W	T7	T6	T5	T4	T3	T2	T1	T0
Reset	0	0	0	0	0	0	0	0

Figure 11-11. SCI Data Register (SCIxD)

11.3 Functional Description

The SCI allows full-duplex, asynchronous, NRZ serial communication among the MCU and remote devices, including other MCUs. The SCI comprises a baud rate generator, transmitter, and receiver block. The transmitter and receiver operate independently, although they use the same baud rate generator. During normal operation, the MCU monitors the status of the SCI, writes the data to be transmitted, and processes received data. The following describes each of the blocks of the SCI.

13.4 Functional Description

This section provides a complete functional description of the IIC module.

13.4.1 IIC Protocol

The IIC bus system uses a serial data line (SDA) and a serial clock line (SCL) for data transfer. All devices connected to it must have open drain or open collector outputs. A logic AND function is exercised on both lines with external pull-up resistors. The value of these resistors is system dependent.

Normally, a standard communication is composed of four parts:

- START signal
- Slave address transmission
- Data transfer
- STOP signal

The STOP signal should not be confused with the CPU STOP instruction. The IIC bus system communication is described briefly in the following sections and illustrated in Figure 13-8.

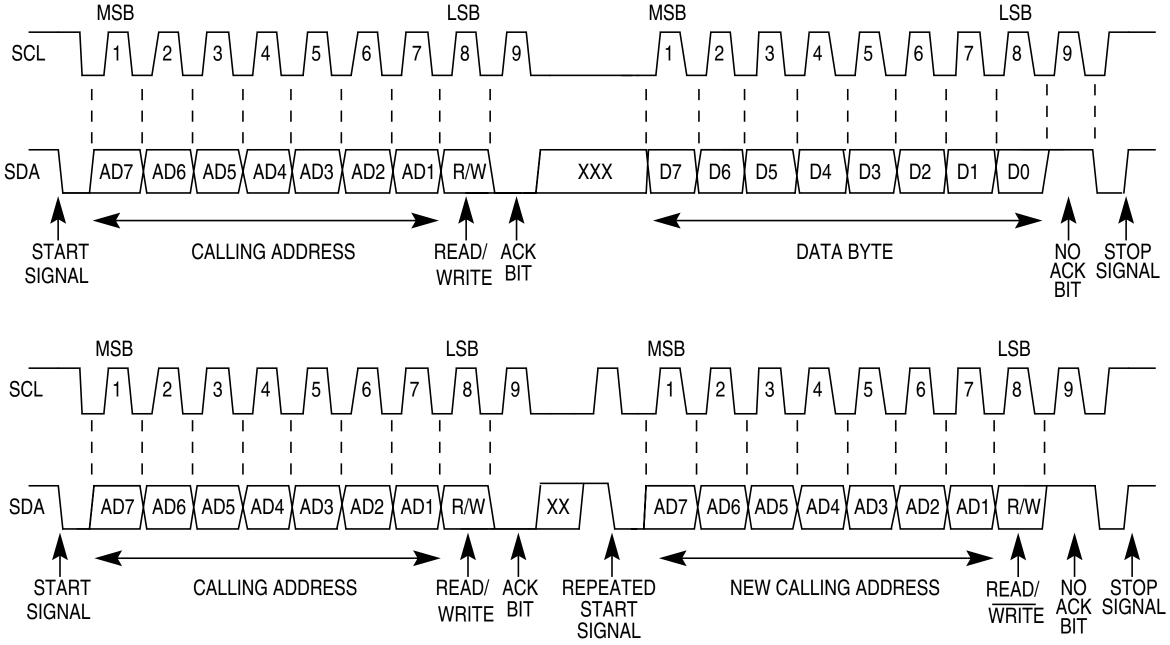


Figure 13-8. IIC Bus Transmission Signals

14.5.7.2 Stop3 Mode With ADACK Enabled

If ADACK is selected as the conversion clock, the ADC continues operation during stop3 mode. For guaranteed ADC operation, the MCU's voltage regulator must remain active during stop3 mode. Consult the module introduction for configuration information for this MCU.

If a conversion is in progress when the MCU enters stop3 mode, it continues until completion. Conversions can be initiated while the MCU is in stop3 mode by means of the hardware trigger or if continuous conversions are enabled.

A conversion complete event sets the COCO and generates an ADC interrupt to wake the MCU from stop3 mode if the ADC interrupt is enabled (AIEN = 1).

NOTE

It is possible for the ADC module to wake the system from low power stop and cause the MCU to begin consuming run-level currents without generating a system level interrupt. To prevent this scenario, software should ensure that the data transfer blocking mechanism (discussed in Section 14.5.4.2, "Completing Conversions) is cleared when entering stop3 and continuing ADC conversions.

14.5.8 MCU Stop1 and Stop2 Mode Operation

The ADC module is automatically disabled when the MCU enters either stop1 or stop2 mode. All module registers contain their reset values following exit from stop1 or stop2. Therefore the module must be re-enabled and re-configured following exit from stop1 or stop2.

14.6 Initialization Information

This section gives an example which provides some basic direction on how a user would initialize and configure the ADC module. The user has the flexibility of choosing between configuring the module for 8-bit or 10-bit resolution, single or continuous conversion, and a polled or interrupt approach, among many other options. Refer to Table 14-6, Table 14-7, and Table 14-8 for information used in this example.

NOTE

Hexadecimal values designated by a preceding 0x, binary values designated by a preceding %, and decimal values have no preceding character.

14.6.1 ADC Module Initialization Example

14.6.1.1 Initialization Sequence

Before the ADC module can be used to complete conversions, an initialization procedure must be performed. A typical sequence is as follows:

1. Update the configuration register (ADCCFG) to select the input clock source and the divide ratio used to generate the internal clock, ADCK. This register is also used for selecting sample time and low-power configuration.

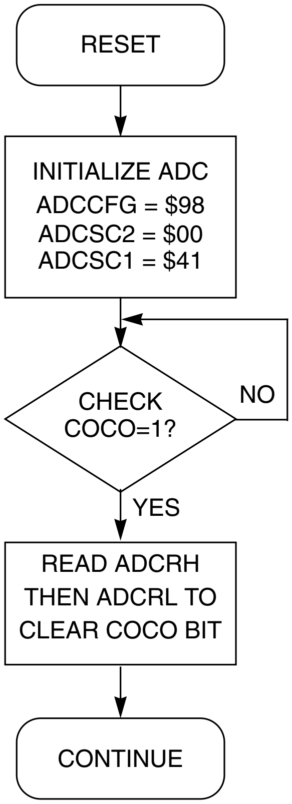


Figure 14-14. Initialization Flowchart for Example

14.7 Application Information

This section contains information for using the ADC module in applications. The ADC has been designed to be integrated into a microcontroller for use in embedded control applications requiring an A/D converter.

14.7.1 External Pins and Routing

The following sections discuss the external pins associated with the ADC module and how they should be used for best results.

14.7.1.1 Analog Supply Pins

The ADC module has analog power and ground supplies (V_{DDAD} and V_{SSAD}) which are available as separate pins on some devices. On other devices, V_{SSAD} is shared on the same pin as the MCU digital V_{SS}, and on others, both V_{SSAD} and V_{DDAD} are shared with the MCU digital supply pins. In these cases, there are separate pads for the analog supplies which are bonded to the same pin as the corresponding digital supply so that some degree of isolation between the supplies is maintained.

When available on a separate pin, both V_{DDAD} and V_{SSAD} must be connected to the same voltage potential as their corresponding MCU digital supply (V_{DD} and V_{SS}) and must be routed carefully for maximum noise immunity and bypass capacitors placed as near as possible to the package.

14.7.2 Sources of Error

Several sources of error exist for A/D conversions. These are discussed in the following sections.

14.7.2.1 Sampling Error

For proper conversions, the input must be sampled long enough to achieve the proper accuracy. Given the maximum input resistance of approximately 7kΩ and input capacitance of approximately 5.5 pF, sampling to within 1/4LSB (at 10-bit resolution) can be achieved within the minimum sample window (3.5 cycles @ 8 MHz maximum ADCK frequency) provided the resistance of the external analog source (R_{AS}) is kept below 5 kΩ.

Higher source resistances or higher-accuracy sampling is possible by setting ADLSMP (to increase the sample window to 23.5 cycles) or decreasing ADCK frequency to increase sample time.

14.7.2.2 Pin Leakage Error

Leakage on the I/O pins can cause conversion error if the external analog source resistance (R_{AS}) is high. If this error cannot be tolerated by the application, keep R_{AS} lower than V_{DDAD} / (2^N*I_{LEAK}) for less than 1/4LSB leakage error (N = 8 in 8-bit mode or 10 in 10-bit mode).

14.7.2.3 Noise-Induced Errors

System noise which occurs during the sample or conversion process can affect the accuracy of the conversion. The ADC accuracy numbers are guaranteed as specified only if the following conditions are met:

- There is a 0.1 μF low-ESR capacitor from V_{REFH} to V_{REFL}.
- There is a 0.1 μF low-ESR capacitor from V_{DDAD} to V_{SSAD}.
- If inductive isolation is used from the primary supply, an additional 1 μF capacitor is placed from V_{DDAD} to V_{SSAD}.
- V_{SSAD} (and V_{REFL}, if connected) is connected to V_{SS} at a quiet point in the ground plane.
- Operate the MCU in wait or stop3 mode before initiating (hardware triggered conversions) or immediately after initiating (hardware or software triggered conversions) the ADC conversion.
  - For software triggered conversions, immediately follow the write to the ADC1SC1 with a WAIT instruction or STOP instruction.
  - For stop3 mode operation, select ADACK as the clock source. Operation in stop3 reduces V_{DD} noise but increases effective conversion time due to stop recovery.
- There is no I/O switching, input or output, on the MCU during the conversion.

There are some situations where external system activity causes radiated or conducted noise emissions or excessive V_{DD} noise is coupled into the ADC. In these situations, or when the MCU cannot be placed in wait or stop3 or I/O activity cannot be halted, these recommended actions may reduce the effect of noise on the accuracy:

- Place a 0.01 μF capacitor (C_{AS}) on the selected input channel to V_{REFL} or V_{SSAD} (this will improve noise issues but will affect sample rate based on the external analog source resistance).

A-Only — Trigger when the address matches the value in comparator A

A OR B — Trigger when the address matches either the value in comparator A or the value in comparator B

A Then B — Trigger when the address matches the value in comparator B but only after the address for another cycle matched the value in comparator A. There can be any number of cycles after the A match and before the B match.

A AND B Data (Full Mode) — This is called a full mode because address, data, and R/W (optionally) must match within the same bus cycle to cause a trigger event. Comparator A checks address, the low byte of comparator B checks data, and R/W is checked against RWA if RWAEN = 1. The high-order half of comparator B is not used.

In full trigger modes it is not useful to specify a tag-type CPU breakpoint (BRKEN = TAG = 1), but if you do, the comparator B data match is ignored for the purpose of issuing the tag request to the CPU and the CPU breakpoint is issued when the comparator A address matches.

A AND NOT B Data (Full Mode) — Address must match comparator A, data must not match the low half of comparator B, and R/W must match RWA if RWAEN = 1. All three conditions must be met within the same bus cycle to cause a trigger.

In full trigger modes it is not useful to specify a tag-type CPU breakpoint (BRKEN = TAG = 1), but if you do, the comparator B data match is ignored for the purpose of issuing the tag request to the CPU and the CPU breakpoint is issued when the comparator A address matches.

Event-Only B (Store Data) — Trigger events occur each time the address matches the value in comparator B. Trigger events cause the data to be captured into the FIFO. The debug run ends when the FIFO becomes full.

A Then Event-Only B (Store Data) — After the address has matched the value in comparator A, a trigger event occurs each time the address matches the value in comparator B. Trigger events cause the data to be captured into the FIFO. The debug run ends when the FIFO becomes full.

Inside Range (A ≤ Address ≤ B) — A trigger occurs when the address is greater than or equal to the value in comparator A and less than or equal to the value in comparator B at the same time.

Outside Range (Address < A or Address > B) — A trigger occurs when the address is either less than the value in comparator A or greater than the value in comparator B.

Table 15-2. BDCSCR Register Field Descriptions (continued)

Field	Description
2 WS	**Wait or Stop Status** — When the target CPU is in wait or stop mode, most BDC commands cannot function. However, the BACKGROUND command can be used to force the target CPU out of wait or stop and into active background mode where all BDC commands work. Whenever the host forces the target MCU into active background mode, the host should issue a READ_STATUS command to check that BDMACT = 1 before attempting other BDC commands. 0 Target CPU is running user application code or in active background mode (was not in wait or stop mode when background became active) 1 Target CPU is in wait or stop mode, or a BACKGROUND command was used to change from wait or stop to active background mode
1 WSF	**Wait or Stop Failure Status** — This status bit is set if a memory access command failed due to the target CPU executing a wait or stop instruction at or about the same time. The usual recovery strategy is to issue a BACKGROUND command to get out of wait or stop mode into active background mode, repeat the command that failed, then return to the user program. (Typically, the host would restore CPU registers and stack values and re-execute the wait or stop instruction.) 0 Memory access did not conflict with a wait or stop instruction 1 Memory access command failed because the CPU entered wait or stop mode
0 DVF	**Data Valid Failure Status** — This status bit is not used in the MC9S08AW60 Series because it does not have any slow access memory. 0 Memory access did not conflict with a slow memory access 1 Memory access command failed because CPU was not finished with a slow memory access

15.4.1.2 BDC Breakpoint Match Register (BDCBKPT)

This 16-bit register holds the address for the hardware breakpoint in the BDC. The BKPTEN and FTS control bits in BDCSCR are used to enable and configure the breakpoint logic. Dedicated serial BDC commands (READ_BKPT and WRITE_BKPT) are used to read and write the BDCBKPT register but is not accessible to user programs because it is not located in the normal memory map of the MCU. Breakpoints are normally set while the target MCU is in active background mode before running the user application program. For additional information about setup and use of the hardware breakpoint logic in the BDC, refer to Section 15.2.4, "BDC Hardware Breakpoint."

15.4.2 System Background Debug Force Reset Register (SBDFR)

This register contains a single write-only control bit. A serial background mode command such as WRITE_BYTE must be used to write to SBDFR. Attempts to write this register from a user program are ignored. Reads always return 0x00.

A.7 Supply Current Characteristics

Table A-8. Supply Current Characteristics

Num	C	Parameter	Symbol	V_{DD} (V)	Typ[1]	Max	Unit	Temp (°C)
1	P	Run supply current[2] measured at (CPU clock = 2 MHz, f_{Bus} = 1 MHz)	RI_{DD}	5	0.750	0.950	mA	–40 to 125°C
				3	0.570	0.770		
2	P	Run supply current[2] measured at (CPU clock = 16 MHz, f_{Bus} = 8 MHz)	RI_{DD}	5	4.90	5.10	mA	–40 to 125°C
				3	3.50	3.70		
3	P	Run supply current[3] measured at (CPU clock = 40 MHz, f_{Bus} = 20 MHz)	RI_{DD}	5	16.8	18.5	mA	–40 to 125°C
				3	11.5	12.5		
4	P	Stop2 mode supply current	$S2I_{DD}$	5	0.900	18.0 60	µA	–40 to 85°C –40 to 125°C
				3	0.720	17.0 50	µA	–40 to 85°C –40 to 125°C
5	P	Stop3 mode supply current	$S3I_{DD}$	5	0.975	20.0 90	µA	–40 to 85°C –40 to 125°C
				3	0.825	19.0 85	µA	–40 to 85°C –40 to 125°C
6	C	RTI adder to stop2 or stop3[4]	$S23I_{DDRTI}$	5	300	500 500	nA	–40 to 85°C –40 to 125°C
				3	300	500 500	nA	–40 to 85°C –40 to 125°C
7	C	LVD adder to stop3 (LVDE = LVDSE = 1)	$S3I_{DDLVD}$	5	110	180	µA	–40 to 125°C
				3	90	160	µA	–40 to 125°C
8	C	Adder to stop3 for oscillator enabled (OSCSTEN =1)[5]	$S3I_{DDOSC}$	5,3	5	8	µA	–40 to 125°C

[1] Typical values are based on characterization data at 25°C unless otherwise stated. See Figure A-5 through Figure A-7 for typical curves across voltage/temperature.

[2] All modules except ADC enabled, but not active. ICG configured for FBE. Does not include any DC loads on port pins.

[3] All modules except ADC active, ICG configured for FBE and does not include any DC loads on port pins

[4] Most customers are expected to find that auto-wakeup from stop2 or stop3 can be used instead of the higher current wait mode. Wait mode typical is 500 µA at 5 V with f_{Bus} = 1 MHz.

[5] Values given under the following conditions: low range operation (RANGE = 0) with a 32.768 kHz crystal, low power mode (HGO = 0), clock monitor disabled (LOCD = 1).

The conducted susceptibility is determined by injecting the transient susceptibility signal on each pin of the microcontroller. The transient waveform and injection methodology is based on IEC 61000-4-4 (EFT/B). The transient voltage required to cause performance degradation on any pin in the tested configuration is greater than or equal to the reported levels unless otherwise indicated by footnotes below the table.

Table A-18. Conducted Susceptibility

Parameter	Symbol	Conditions	f_{OSC}/f_{BUS}	Result	Amplitude[1] (Min)	Unit
Conducted susceptibility, electrical fast transient/burst (EFT/B)	V_{CS_EFT}	V_{DD} = 5.5V T_A = +25°C package type 64 QFP	32768 Hz crystal 2 MHz Bus	A	±0 ±2.0[2]	kV
				B	±2.5	
				C	±3.0	
				D	>±3.0	

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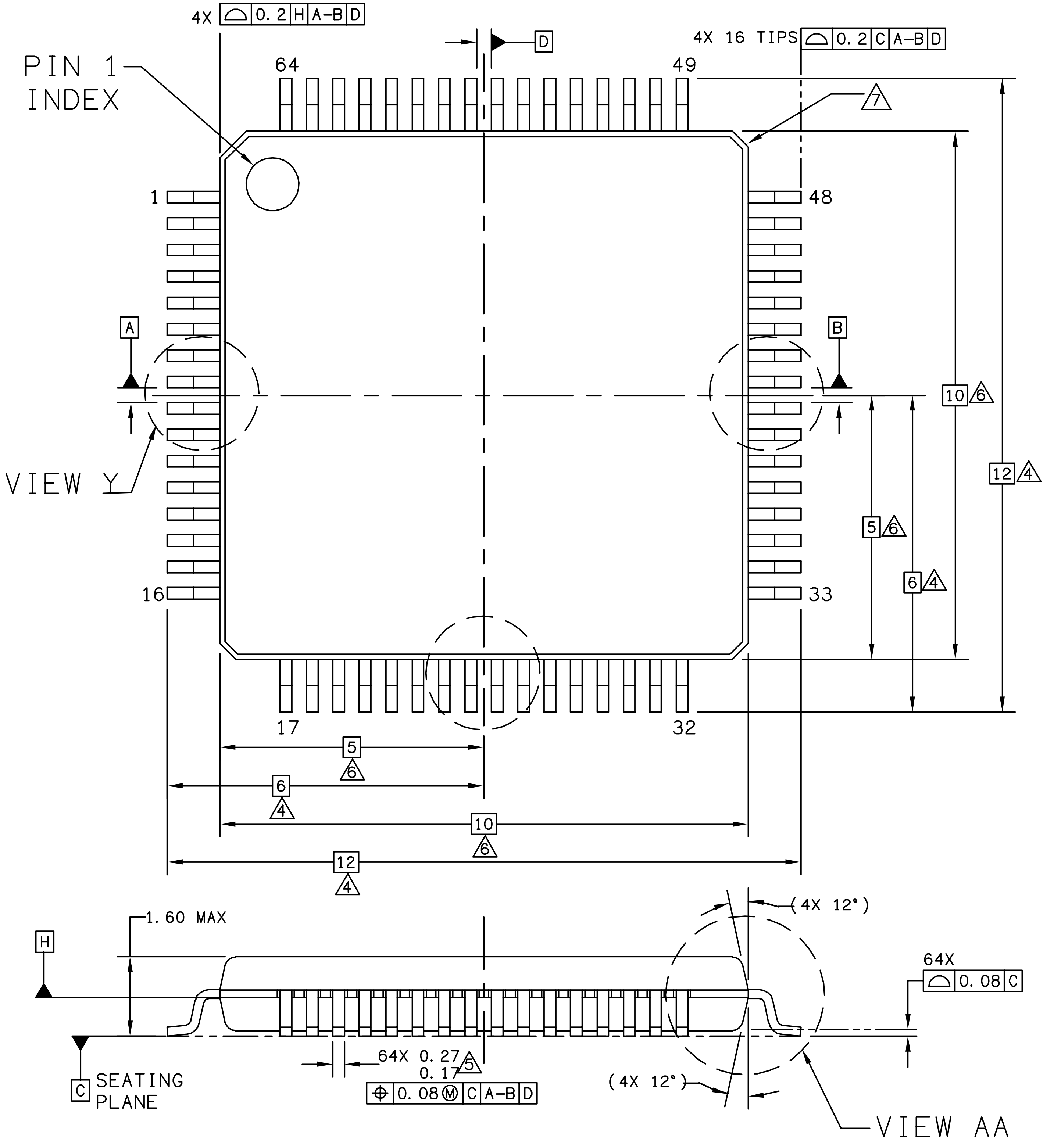
[1] Data based on qualification test results. Not tested in production.

[2] The $\overline{\text{RESET}}$ pin is susceptible to the minimum applied transient of 220 V. All other pins have a result of A up to a minimum of 2000V.

The susceptibility performance classification is described in Table A-19.

Table A-19. Susceptibility Performance Classification

Result	Performance Criteria	
A	No failure	The MCU performs as designed during and after exposure.
B	Self-recovering failure	The MCU does not perform as designed during exposure. The MCU returns automatically to normal operation after exposure is removed.
C	Soft failure	The MCU does not perform as designed during exposure. The MCU does not return to normal operation until exposure is removed and the RESET pin is asserted.
D	Hard failure	The MCU does not perform as designed during exposure. The MCU does not return to normal operation until exposure is removed and the power to the MCU is cycled.
E	Damage	The MCU does not perform as designed during and after exposure. The MCU cannot be returned to proper operation due to physical damage or other permanent performance degradation.



MECHANICAL OUTLINE

PRINT VERSION NOT TO SCALE

TITLE:
64LD LQFP,
10 X 10 X 1.4 PKG,
0.5 PITCH, CASE OUTLINE

DOCUMENT NO: 98ASS23234W

REV: E

CASE NUMBER: 840F-02

11 AUG 2006

STANDARD: JEDEC MS-026 BCD